

## General Description

The QM2538N3 is the highest performance trench N-Channel MOSFET with extreme high cell density, which provide excellent RDSON and gate charge for most of the Battery MOSFET Switch. The QM2538N3 meet the RoHS and Green Product requirement.

## Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Green Device Available
- Embedded ESD Protection
- HBM 2KV / MM200V Verified

## Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	20	V
$V_{GS}$	Gate-Source Voltage	$\pm 8$	V
$I_D@T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ 4.5V^1$	56	A
$I_D@T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ 4.5V^1$	35	A
$I_D@T_A=25^\circ C$	Continuous Drain Current, $V_{GS} @ 4.5V^1$	13	A
$I_D@T_A=70^\circ C$	Continuous Drain Current, $V_{GS} @ 4.5V^1$	10	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	100	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	45	mJ
$I_{AS}$	Avalanche Current	30	A
$P_D@T_C=25^\circ C$	Total Power Dissipation <sup>4</sup>	31	W
$P_D@T_A=25^\circ C$	Total Power Dissipation <sup>4</sup>	1.6	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	---	75	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	---	4	°C/W

**N-Channel 20V Fast Switching MOSFET**
**Electrical Characteristics ( $T_J=25^\circ C$ , unless otherwise noted)**

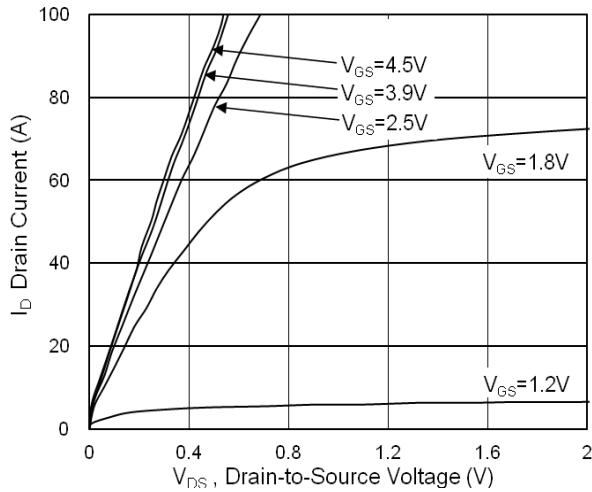
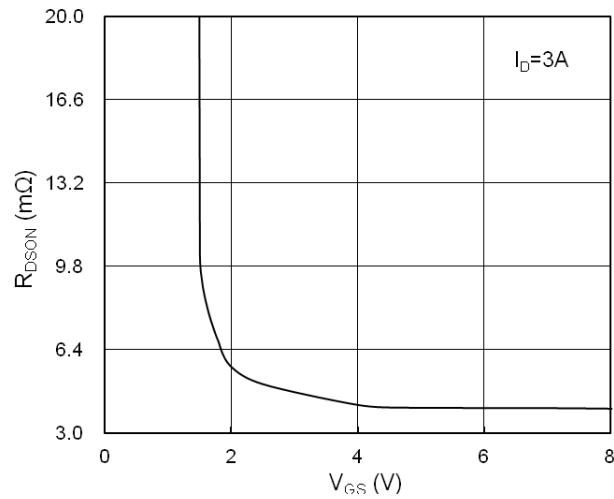
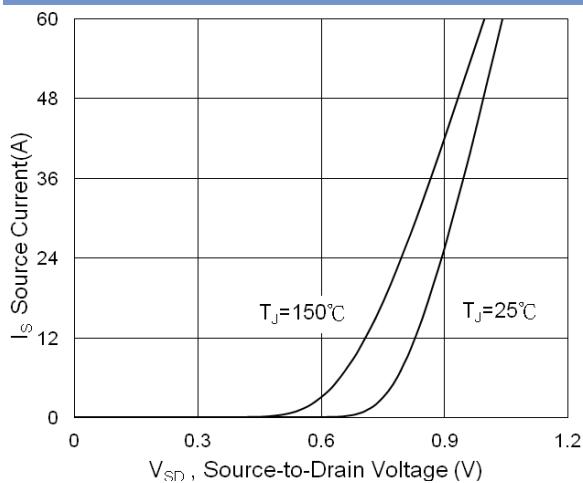
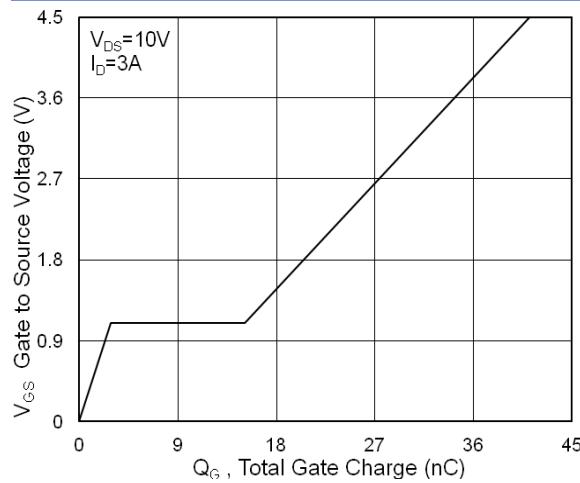
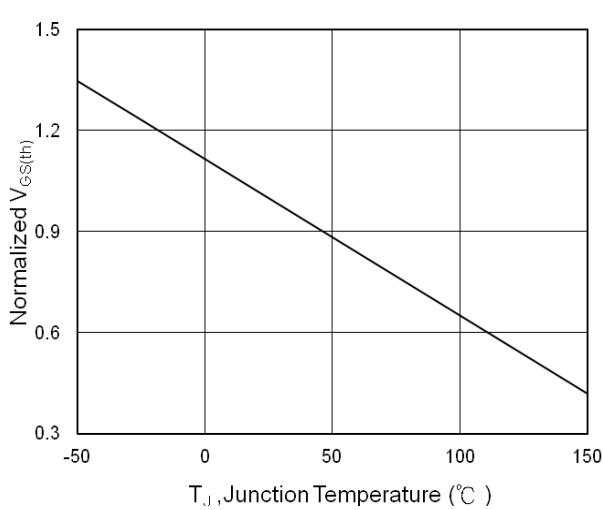
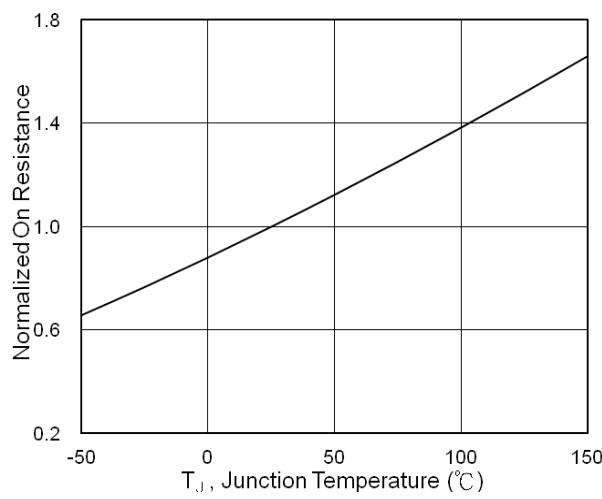
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	20	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	$BV_{DSS}$ Temperature Coefficient	Reference to $25^\circ C, I_D=1mA$	---	0.01	---	$mV/C$
$R_{DS(ON)}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=4.5V, I_D=3A$	2.3	3.9	6.0	$m\Omega$
		$V_{GS}=4.0V, I_D=3A$	2.4	4.0	6.8	
		$V_{GS}=3.9V, I_D=3A$	2.4	4.0	6.8	
		$V_{GS}=3.8V, I_D=3A$	2.4	4.0	6.8	
		$V_{GS}=3.1V, I_D=3A$	2.6	4.4	7.5	
		$V_{GS}=2.5V, I_D=3A$	2.8	4.7	8.0	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	0.5	0.7	1	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	-2.7	---	$mV/C$
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=16V, V_{GS}=0V, T_J=25^\circ C$	---	---	1	$\mu A$
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS}=\pm 8V, V_{DS}=0V$	---	---	$\pm 10$	$\mu A$
$g_{fs}$	Forward Transconductance	$V_{DS}=5V, I_D=3A$	---	40	---	S
$R_g$	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1MHz$	---	19.2	---	$\Omega$
$Q_g$	Total Gate Charge	$V_{DS}=10V, V_{GS}=4.5V, I_D=3A$	---	41.1	---	$nC$
$Q_{gs}$	Gate-Source Charge		---	2.9	---	
$Q_{gd}$	Gate-Drain Charge		---	12.2	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=15V, V_{GS}=4.5V, R_G=3.3\Omega$	---	8.3	---	$ns$
$T_r$	Rise Time		---	34.6	---	
$T_{d(off)}$	Turn-Off Delay Time		---	406.7	---	
$T_f$	Fall Time		---	189.8	---	
$C_{iss}$	Input Capacitance	$V_{DS}=10V, V_{GS}=0V, f=1MHz$	---	2571	---	$pF$
$C_{oss}$	Output Capacitance		---	334	---	
$C_{rss}$	Reverse Transfer Capacitance		---	318	---	

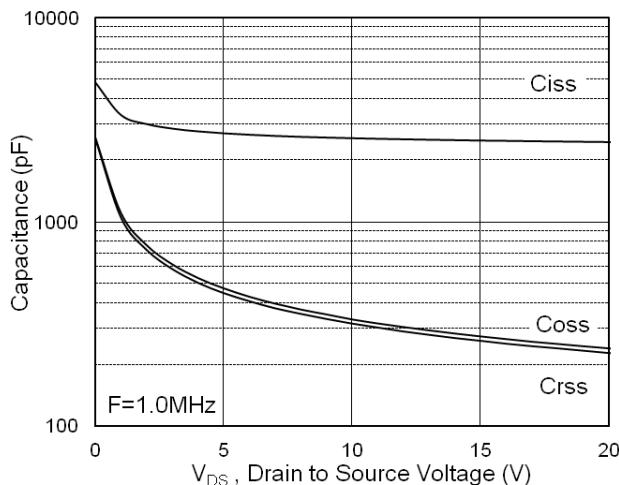
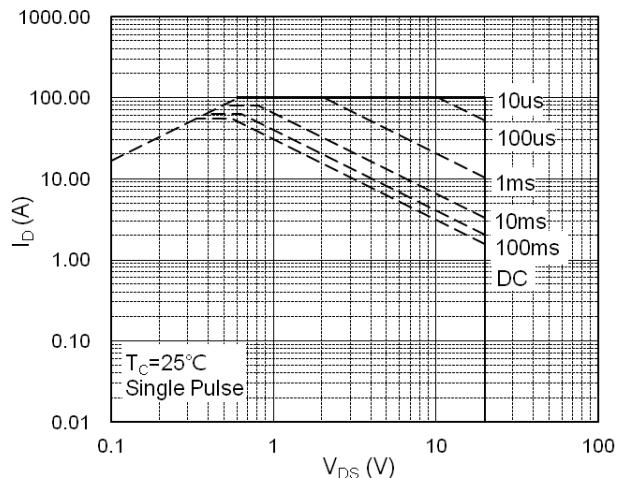
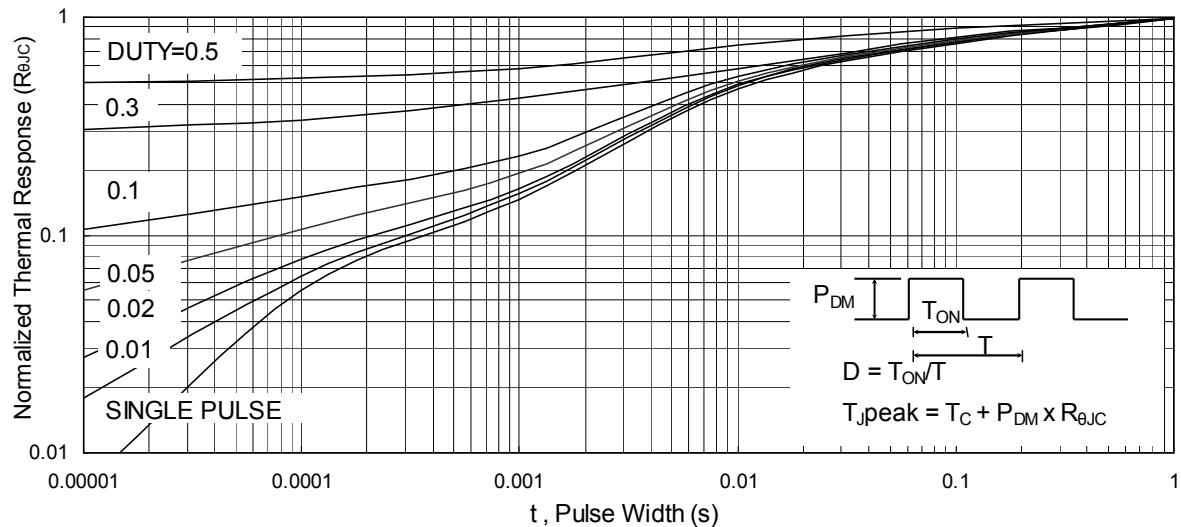
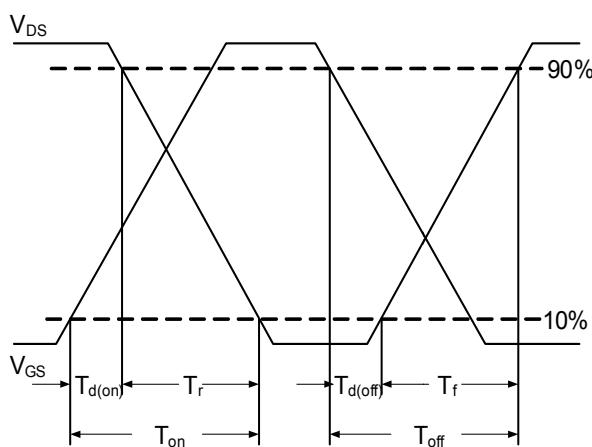
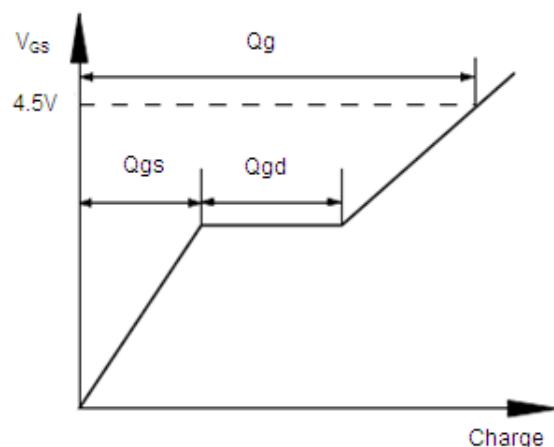
**Diode Characteristics**

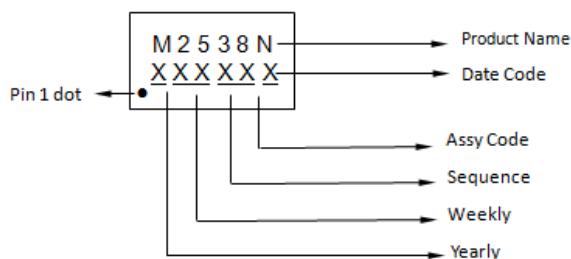
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_s$	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0V$ , Force Current	---	---	56	A
$I_{SM}$	Pulsed Source Current <sup>2,5</sup>		---	---	100	A
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0V, I_s=1A, T_J=25^\circ C$	---	---	1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.Pulse width limited by maximum junction temperature.
- 3.The EAS data shows Max. rating . The test condition is  $V_{DD}=25V, V_{GS}=8V, L=0.1mH$
- 4.The power dissipation is limited by  $150^\circ C$  junction temperature
- 5.The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

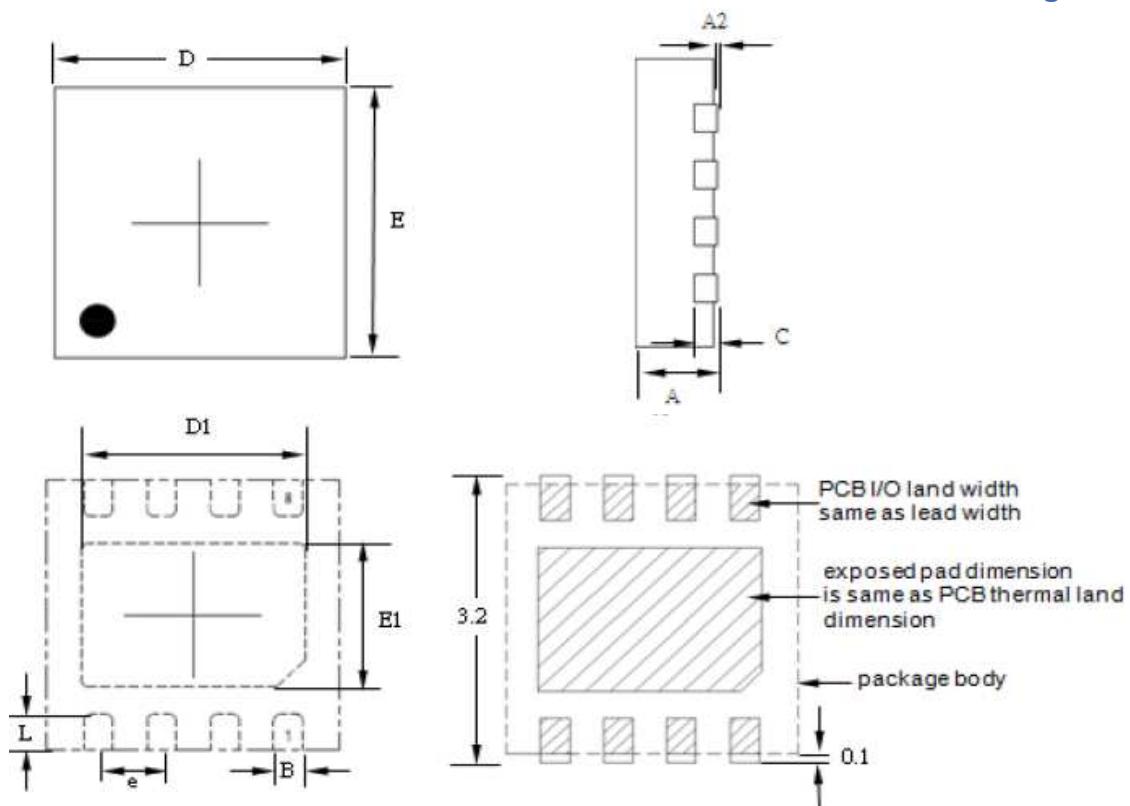
**N-Channel 20V Fast Switching MOSFET**

**Fig.1 Typical Output Characteristics**

**Fig.2 On-Resistance vs. Gate-Source**

**Fig.3 Forward Characteristics of reverse**

**Fig.4 Gate-Charge Characteristics**

**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$** 

**Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$**

**N-Channel 20V Fast Switching MOSFET**

**Fig.7 Capacitance**

**Fig.8 Safe Operating Area**

**Fig.9 Normalized Maximum Transient Thermal Impedance**

**Fig.10 Switching Time Waveform**

**Fig.11 Gate Charge Waveform**

**N-Channel 20V Fast Switching MOSFET**


X	XX	XX	X
1' st code	2 ~ 3nd code	4 ~ 5th code	6th code
Year (The 1' st code display with English letter when the wafer supplier is second source)			
0:2010	A:2010	01	01
1:2011	B:2011		
2:2012	C:2012	53	99
3:2013	D:2013		
4:2014	E:2014		
5:2015	F:2015		
6:2016	G:2016		
7:2017	H:2017		
8:2018	I:2018		
9:2019	J:2019		
0:2020	A:2020		
1:2021	B:2021		

**Fig.12 Top Marking**

**N-Channel 20V Fast Switching MOSFET**


SYMBOLS	MILLIMETERS			INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	0.70	0.75	0.80	0.028	0.030	0.031
A2	0.00	--	0.05	0.000	--	0.002
B	0.25	0.30	0.35	0.010	0.012	0.014
C	0.20	0.203	0.21	0.008	0.008	0.008
D	2.90	3.00	3.10	0.114	0.118	0.122
E	2.90	3.00	3.10	0.114	0.118	0.122
D1	2.25	2.30	2.35	0.089	0.091	0.093
E1	1.55	1.60	1.65	--	0.063	--
L	0.35	0.40	0.45	0.014	0.016	0.018
e	--	0.65	--	--	0.026	--

**Note:**

1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
2. CONTROLLING DIMENSION IS MILLIMETER CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACTLY

**Revision History:**

2015/02/12: Change A from 0.8~1.0 (mm) to 0.7~0.8 (mm)

**Fig.13 DFN 3X3 Package Outline Drawing**